

RAPID THROUGHPUT SURFACE TOPOGRAPHICAL ANALYSIS

ABSTRACT OF THE DISCLOSURE

A library of materials is screened for characteristics. Accordingly, a library of materials is provided and an electromagnetic wavefront is directed at each member of the library. The electromagnetic wavefront is monitored for a response after the wavefront encounters the at least for sample materials. Thereafter, the response of the electromagnetic wavefront is correlated to a characteristic of the at least four sample materials.